

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

 ATTY. DOCKET NO.
044117-0143

 SERIAL NO.
10/539,771

 APPLICANT
Eric PINET, et al.

(Substitute for form 1449/PTO)

 FILING DATE
January 10, 2006

 GROUP
1797
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OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)

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/Samuel Siefke/

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